

A Symbolic Model-Checking Framework for Transient Fault Robustness Classification and Quantification

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Outline

- 1 Motivation
- 2 Fault and Reparation Models
- 3 Robustness classification and quantification
- 4 Experiments
- 5 Conclusion and Perspectives

Motivation

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Context : Circuits' Robustness

Robustness

Ability of a circuit to behave “correctly” even in presence of some perturbations.

Possible causes of perturbation

- Fault :
 - Manufacturing defect, component aging (permanent / sporadic)
 - Particle strikes / cross-talk coupling (transient)
- Error : visible consequence of a fault,
- Failure : non conform behavior of the system.

Several robustness criteria

- Error detection and external reset
- Conformance to a set of reference behaviors

Contributions

Needs

Evaluate the robustness level of a circuit for a given perturbation type and robustness criterion

- Localization of areas to be protected
- Selection and Validation of protection mechanisms

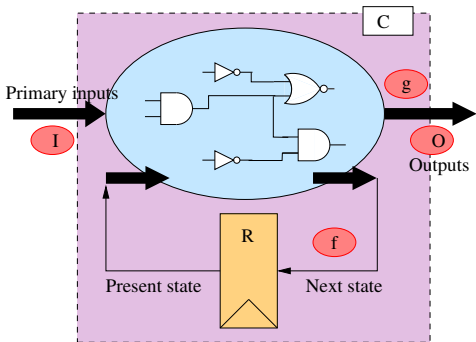
Our Proposal

Context :

- Synchronous digital circuits (post-synthesis RTL description)
- Transient Faults (multiple occurrence in time and space)

Contributions :

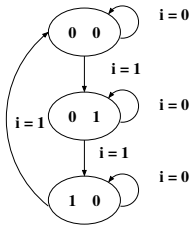
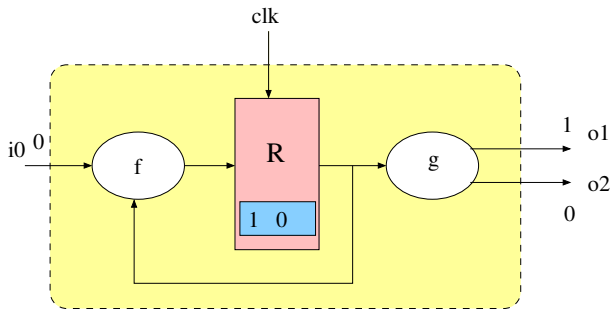
- Faults and Reparation Models
- Robustness classification and quantification



Reachable States and Sequences

- $\mathbf{r} \in 2^R$: a state of C
- \mathbf{R}_0 : the set of initial state:
- $\mathbf{i}_1.\mathbf{i}_2 \dots \mathbf{i}_{n-1}$: an input sequence
- $f(\mathbf{r}, \mathbf{i}_1.\mathbf{i}_2 \dots \mathbf{i}_{n-1})$: a state sequence
- $g(\mathbf{r}, \mathbf{i}_1.\mathbf{i}_2 \dots \mathbf{i}_{n-1})$: an output sequence
- $reach(C)$: the set of reachable states of C from \mathbf{R}_0

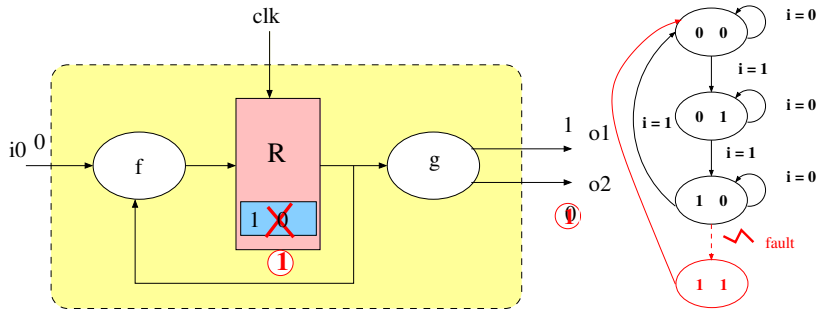
A fault occurrence producing an error



Faults

- Single or multiple bit flips in memory elements (registers).
- Errors are observable on the output of the system

A fault occurrence producing an error



Faults

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Types of Robustness Analysis

Experimental Outcomes (from [Lev10])

- Classification of soft errors wrt. a list of pre-defined effects
- Quantification of derating factors : percentage of errors propagating to outputs (block or system level)
- Identification of propagation paths
- Identification of critical locations (register grading)
- Proof of a given set of properties (detection/correction/tolerance mechanisms)

Analysis Means

Simulation-based

- Enumeration of fault injection / not exhaustive / statistical simulation + confidence margins [Leveugle 2009][Daveau 2010]
- Hardware emulation with ad-hoc architectures (failure rate, register grading) [Entrena 2007-2009]

Formal Methods

- Model-checking
 - Equivalence checking of faulty wrt. golden [Leveugle 2005][Drechsler,Fey 2008-2010]
 - Preservation of initial specification [Seshia 2007-2009][Krautz 2007]
- Theorem-Proving
 - Correctness of detection + correction mechanisms (ACL2) [Pierre 2009]

Our Concern : Self-stabilization evaluation

After a period of particles strikes, how to ensure the circuit's return into a *safe behavior*?

Analyzing the self-healing capabilities of circuits

Concerns of our measures:

- ① Rates of reparation ability
 - Number of *potentially* and *eventually* repairable states
- ② Reparation Promptness
 - Bounds of the reparations sequences

This allows designers to

- Choose part of design to be hardened
- Choose between different implementations of the same functionality

Fault and Reparation Models

- 1 Motivation
- 2 Fault and Reparation Models**
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Type of faults

- Errors appear as *bit-flips* on register elements.
- There exists a set of *protected* register elements $P \subseteq R$ (this set may be empty).

Fault occurrences

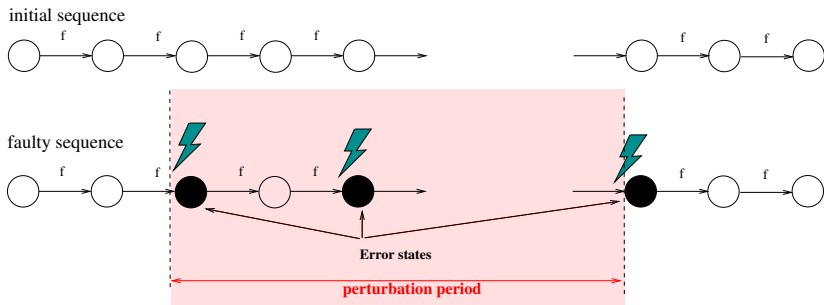
- Spacial multiplicity : faults may occur in multiple registers, except in protected registers.
- Temporal multiplicity : faults may occur at different time instants.

Faulty sequence

A faulty sequence is characterized by the following properties:

- ① It begins in an initial state of the circuit,
- ② At least one effective fault occurred (at least one bit is affected),
- ③ After a while, the perturbation period ends.

The set of faulty sequences is denoted by FS .



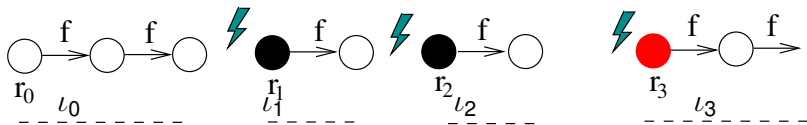
Error and End of disturbance states

An *error* state follows any fault. The *end of disturbance* state is the state following the last fault occurring along a disturbance period.

End of disturbance states (Eds)

A state \mathbf{r} is a *end of disturbance state* iff there exists a faulty sequence $\sigma = (\mathbf{r}_0, \iota_0) \cdot (\mathbf{r}_1, \iota_1) \dots (\mathbf{r}_n, \iota_n)$ respecting f and such that $\mathbf{r}_n = \mathbf{r}$. Such a faulty sequence σ contains a unique end of disturbance state \mathbf{r} .

Along σ , states $\mathbf{r}_1, \mathbf{r}_2, \mathbf{r}_n$ are also *Error* states.



Reparation model

The Reparation Model $T = \langle Ref, Eq \rangle$ is composed of

- a Reference function $Ref : FS \mapsto 2^{2^R}$,
- an Equivalence relation $Eq \in 2^{2^R} \times 2^{2^R}$,

Reference Function

Give the set of of *recovery states*.

This set may depend on the initial state and the input sequence.

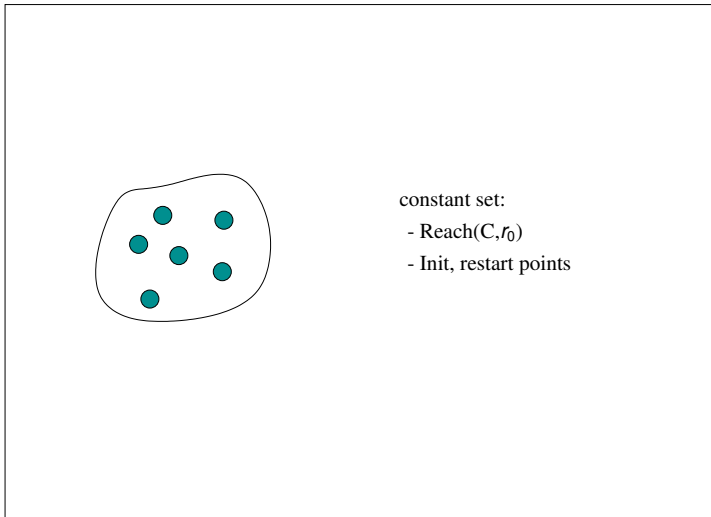
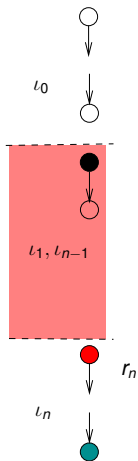
Equivalence relation

Any equivalence relation between states after a perturbation period and those returned by the reference function (equality, observational equivalence,...)

Several Reference functions

faulted sequence

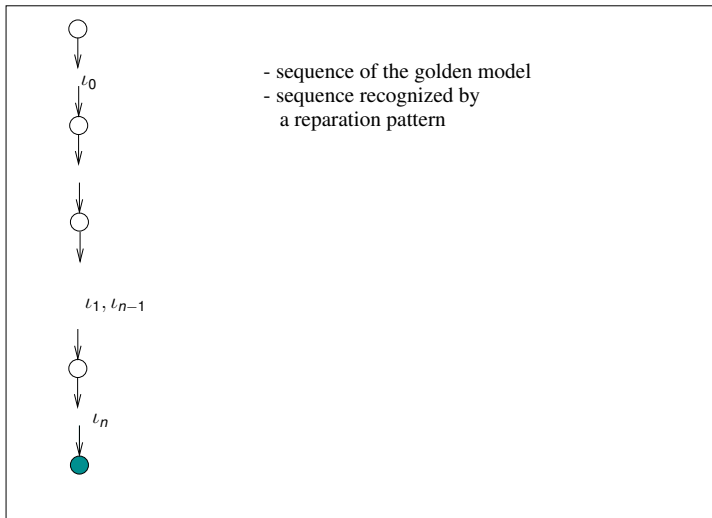
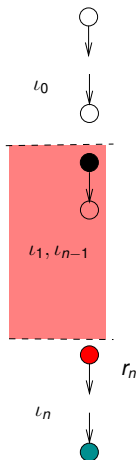
Examples of states returned by the reference function



Several Reference functions

faulted sequence

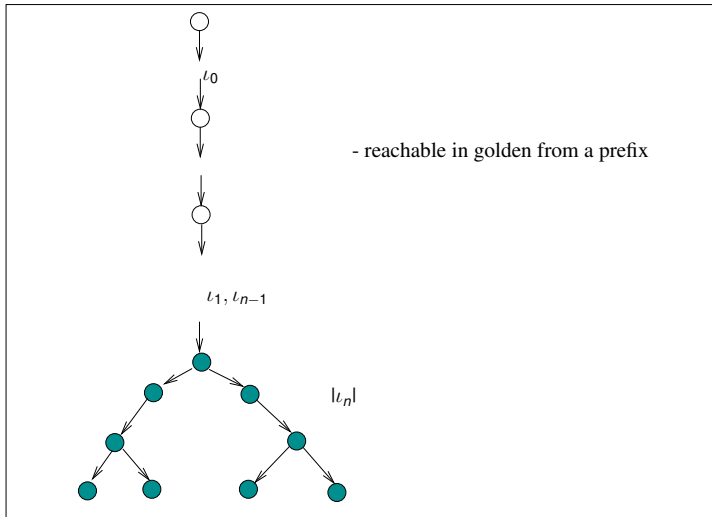
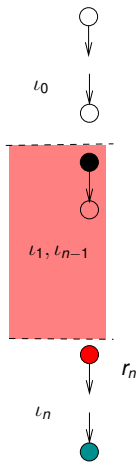
Examples of states returned by the reference function



Several Reference functions

faulted sequence

Examples of states returned by the reference function



Repairing sequence

Definition (Repairing Sequence)

A faulty sequence $\sigma = (\mathbf{r}_0, \iota_0) \cdot (\mathbf{r}_1, \iota_1) \dots (\mathbf{r}_n, \iota_n)$ is a *repairing sequence* iff one of the two following cases holds:

- It contains a strict prefix which is a repairing sequence.
- The prolongation of \mathbf{r}_n by ι_n leads to a state equivalent to a state given by the reference function (for the same input sequence). i.e. $\exists \mathbf{r} \in \mathbf{Ref}(\mathbf{r}_0, \iota_0, \dots, \iota_n)$ such that $(f(\mathbf{r}_n, \iota_n), \mathbf{r}) \in Eq$

Reparable and Non-Reparable states

Definition (Reparable and Non-Reparable states)

An end of disturbance state \mathbf{r} is:

- a **reparable state** iff all faulty sequences having \mathbf{r} as end of disturbance state are repairing;
- a **potentially-reparable state** if \mathbf{r} some of the faulty sequences are repairing, but not all of them.
- a **non-reparable state** in the other cases.

Robustness Measures

Reparable states measure :

$$\nu_{pot} = \frac{|PotentiallyReparable|}{|Eds|}$$

$$\nu_{ev} = \frac{|Reparable|}{|Eds|}$$

Length of reparation sequences:

For each k :

count non-looping elementary reparation sequences of length k.

Robustness classification and quantification

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Classification Criteria

Question : What is the reference, and how to compare with it ?

Observed elements

- Internal registers + outputs : complete state of the circuit
- Outputs only : observational equivalence. $\mathbf{r} \equiv \mathbf{r}'$ iff:

$$\forall \iota \in (2^I)^*, \forall o \in O, g(f(\mathbf{r}, \iota))[o] = g(f(\mathbf{r}', \iota))[o]$$

Divergence acceptance

- No divergence : the environment is not able to support any non correct output at any time (communication protocols without recovery support)
- Finite divergence : the environment tolerates some non correct outputs for a while (video stream : corrupted images, commit-rollback execution)
- Infinite divergence : switch to a downgraded functioning

Robustness Classification

- | | |
|----------------|---|
| Class 1 | no observable difference for any output from the golden model
-> [Lev05], [KPJ ⁺ 06], [FD08, FSD09], itc-99 |
| Class 2 | initial states satisfy the same set of (CTL) properties
-> [SLM07], spacewire ctrl |
| Class 3 | finite observable difference. Will eventually become equivalent to the golden model for the same input sequence. |
| Class 4 | infinite observable difference. Will eventually return into a set of Safe (Recovery) states
-> [BBC ⁺ 09, BBE ⁺ 11], gcd, multipliers, ATM, itc-99 |

Classes 1, 3 and 4 are expressible with our reparation model while class 2 is not.

Robustness Classification

Let $\sigma = (\mathbf{r}_0, \iota_0).(\mathbf{r}_1, \iota_1) \dots (\mathbf{r}_n, \iota_n)$ be a faulty sequence,

Robustness	<i>Ref</i>	<i>Eq</i>
Class 1	<i>Ref</i> ₁	≡
Class 2	not definable	
Class 3	<i>Ref</i> ₃	= or ≡
Class 4	<i>Ref</i> ₄	= or ≡

$$Ref_1(\sigma) = \begin{cases} \{f(\mathbf{r}_0, \iota_0 \dots \iota_{n-1})\} & \text{if } \iota_n = \epsilon \\ \emptyset & \text{otherwise} \end{cases}$$

$$Ref_3(\sigma) = \{f(\mathbf{r}_0, \iota_0 \dots \iota_n)\}$$

$$Ref_4(\sigma) = \begin{cases} Inv & \text{if } cd(\sigma) \\ \emptyset & \text{otherwise} \end{cases}$$

State quantification

- Build an instrumented circuit embedding the reference function,
- Compute $|Eds|$ according to the fault model,
- Compute $|Potentially\ Repairable|$, $|Repairable|$ by symbolic Model Checking.

Repairing velocity

- Compute *min* and *max* length of elementary repairing sequences
- Compute distribution of elementary repairing sequences between *min* and *max*

Measure Computation for each robustness class



Computation of EDS (multiple fault model)

- *Each faulty state is potentially an end of disturbance state.*
- Compute the set *Eds* :
 - 1 $S = \text{post}^*(r_0)$
 - 2 $S' = \text{Inject any fault in } S \text{ (according to } P)$
 - 3 $S'' = \text{post}^*(S')$
 - 4 if $S'' \neq S : S \leftarrow S''$, goto 2 else return S''

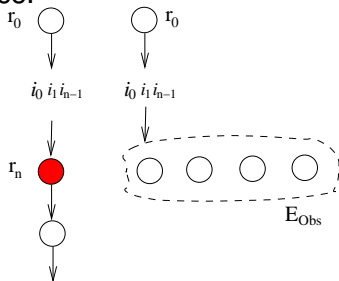
Fault injection is based on BDD manipulation of the symbolic state space. The effectiveness of the fault is ensured.

Computation of repairing states, class 1

Reference function : no observable difference.

Computation of repairing states

- 1 Build $S = F \parallel G$
- 2 Compute $Eds(S)$ (all registers of G are protected) : of the form $(\mathbf{r}_f, \mathbf{r}_g)$
- 3 Repairable are states in Eds satisfying $\mathbf{r}_f \equiv \mathbf{r}_g$, i.e. satisfying $AG(\mathbf{o}_f = \mathbf{o}_g)$

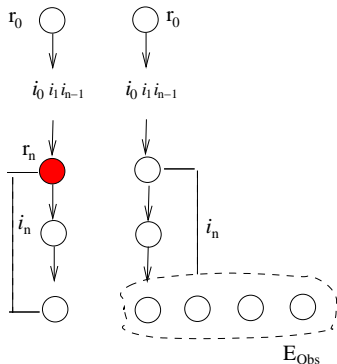


Computation of repairing states, class 3

Reference function : finite observable difference.

Computation of repairing states

- 1 Build $S = F \parallel G$
- 2 Compute $\text{Eds}(F \parallel G)$ (all registers of G are protected)
- 3 Compute
 - Repairable = $\mathbf{r} \models \text{Eds} \wedge \text{AF}(\text{AG}(\mathbf{o}_f = \mathbf{o}_g))$
 - Potentially repairable = $\mathbf{r} \models \text{Eds} \wedge \text{EF}(\text{AG}(\mathbf{o}_f = \mathbf{o}_g))$
 - Non repairable = $\mathbf{r} \models \text{Eds} \wedge \text{EG}(\neg(\text{AG}(\mathbf{o}_f = \mathbf{o}_g)))$

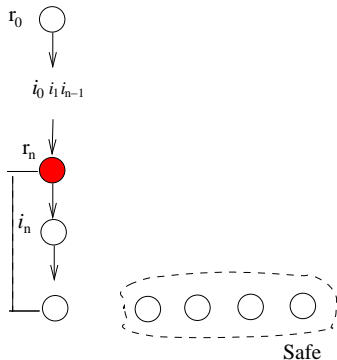


Computation of repairing states, class 4

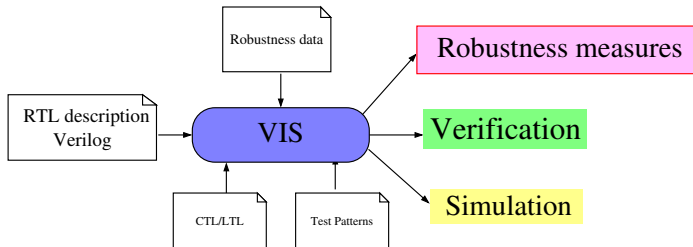
Reference function : will eventually return into a set of Safe (Recovery) states

Computation of repairing states

- 1 Compute $E_{ds}(F)$
- 2 Compute
 - reparable = $\mathbf{r} \models E_{ds} \wedge AF(\text{Safe})$
 - potentially reparable = $\mathbf{r} \models E_{ds} \wedge EF(\text{Safe})$
 - non reparable = $\mathbf{r} \models E_{ds} \wedge EG(\neg \text{Safe})$



Robustness Analysis framework

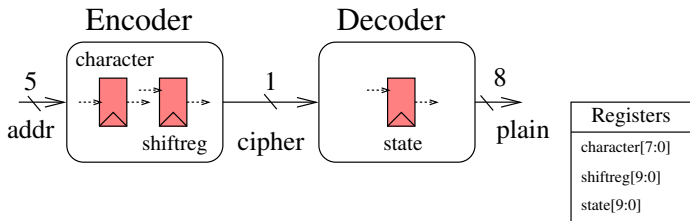


The VIS group. VIS : A System for Verification and Synthesis. In R. Alur and T. A. Henzinger, editors, *CAV'96: Proceedings of the 8th International Conference on Computer Aided Verification*, volume 1102 of *LNCS*. Springer-Verlag, 1996

Experiments

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Case study: a Huffman encoder-decoder [project of X. Wang, 2011] (1)



Static encoding/decoding

- Encoder: Read a character and return the encoding form bit by bit
- Decoder: Explore the encoding tree and return the character.

Huffman: First analysis

Robustness analysis without any protection

Rob	Fault	$ Err $	ν_{ev}	ν_{pot}	time
Rob4	SEU	61654	48%	99.5%	0
	MEU	2.68e+08	7%	99.8%	0
Rob3	SEU	1.43e+06	45%	99.6%	1min
	MEU	2.36e+11	0.6%	99.8%	1min
Rob1	SEU	1.43e+06	30.5%	47%	-
	MEU	2.36e+11	0%	0%	-

Originally reachable states : 878

Huffman: Register grading

Which registers are critical ?

Protected registers	Fault type	Rob 4		Rob 3		Rob 1
		ν_{ev}	ν_{pot}	ν_{ev}	ν_{pot}	$\nu_{ev} = \nu_{pot}$
character	SEU	25.17%	99.3%	22.63%	99.3 %	2.72%
	MEU	7.07%	99.8%	0.59%	99.8%	0%
state	SEU	58.45%	99.3%	55.13%	100%	44.61%
	MEU	24.73%	99.8%	2.22%	100%	0.10%
shiftreg	SEU	62.80%	100%	58.90%	100%	47.30%
	MEU	10.92%	100%	13.86%	100%	0.62%
character/ state	SEU	25.45%	99.8%	19.23%	99.8%	0.30%
	MEU	24.89%	99.8%	2.12%	100%	0%
character/ shiftreg	SEU	24.62%	100%	26.02%	100%	5.14%
	MEU	7.39%	100%	13.79%	100%	0.53%
state/ shiftreg	SEU	100%	100%	100%	100%	100%
	MEU	100%	100%	100%	100%	100%

Huffman: Strengthening robustness

Two approaches

- Triplicate register: replace register by TMR
- Periodic reset mechanism

Robustness analysis with "reset" protection

Class	Fault	ν_{ev}	ν_{pot}
Rob4	SEU	100%	100%
	MEU	100%	100%
Rob3	SEU	78.8%	100%
	MEU	4.12%	100%
Rob1	SEU	33.3%	-
	MEU	0%	-

Case study: a Huffman encoder-decoder (8)

Protection mechanisms :

TMR

- adapted for single spatial / multiple temporal faults
- immediate correction -> class 1 robustness
- costly : add of $2 * 20$ FF for a initial circuit of 28 FF + vote glue logic

Periodic reset

- adapted for multiple spatial / multiple temporal faults
- delayed reparation -> class 4 robustness (but not class 3)
- cheap : add a 3 bit counter.

Conclusion and Perspectives

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New metrics

- Identification of several robustness criteria wrt. self-healing capabilities
- Metrics to determine
 - the minimal set of registers to be protected for a given architecture
 - select a more robust architecture between several possibilities
 - evaluate several reparation strategies

A Robustness Analysis Framework

- Single or Multiple transient faults by symbolic management
- Early in a design flow
- First implementation within a classical model checker (VIS)

Perspectives (1)

Framework improvements

- Robustness classification : something in-between Class 3 and 4
- Calculus :
 - Compositional reasoning
 - Use of abstractions

Evaluation and enhancement of the robustness level

- Automatic insertion of reparation patterns
 - Localization + correction with ad-hoc structures (TMR, ECC)
- Insertion of several functioning modes and switch
 - Synthesis of external controller driving execution modes

Perspectives (2)

Other levels of modeling

Asynchronous concurrent tasks, SystemC-TLM

Links between high-level and RTL robustness measures

Robustness Debug

How to combine robustness measures and properties to identify causes of non-robustness ?

Other robustness qualification

How to avoid the pure state-based model ? Combination of identified state-space structures ?